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L9	1	8 and (slice near4 image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:41
L10	0	("9and(calculat\$4ormeasur\$4orcom put\$4)").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:42
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L12	0	11 and sag	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:42
L13	35	sag and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:16
L14	22	1 and 13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:04
L15	7	14 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46
L16	5	15 and (calculat\$4 or comput\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17

L17	5	16 and sag	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08
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L19	5	18 and (slice)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:09
L20	445	(swag or bend\$4 or sag) and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:23
L21	231	1 and 20	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L22	59	21 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L23	56	22 and (calculat\$4 or comput\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L24	56	23 and position\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:18

L25	47	24 and (accumulat\$4 or collect\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:18
L26	4	((swag or bend\$4 or sag) near4 (correct\$4)) and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:28
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L28	2	27 and tabl\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:29
L29	2	28 and stor\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:30
L30	0	29 and (acquair\$4 near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:30
L31	1	29 and (acquir\$4 near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:31
L32	0	31 and (imag\$4 near4 position)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:31

L33	1	31 and (imag\$4 near4 position\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:38
L34	1	33 and stor\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46
L35	1	34 and adjustment\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:47
L36	0	35 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46

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Design and implementation of a series voltage sag compensator under practical utility conditions

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This paper appears in: Industry Applications, IEEE Transactions on

Publication Date: May-June 2003

On page(s): 844- 853

Volume: 39, Issue: 3

ISSN: 0093-9994

INSPEC Accession Number: 7648259

Abstract:

Voltage sags have become one of the most important power quality concerns recent years. According to survey results across the US, voltage sags and short duration power outages account for 92% of power quality problems encountered by industrial customers. Voltage sags often cause undervoltage faults in various sensitive loads and subsequently interrupt the manufacturing processes. Such interruptions often inflict severe losses for industries. In Taiwan, ROC, most high-tech manufacturers use uninterruptible power supplies to avoid interruptions, but the cost effectiveness of such an approach remains unclear. As the utility grid continues to improve the reliability of electric power, the inverter-based voltage sag compensator has become a viable solution to prevent production interruptions resulting from voltage sags. The existing sag compensation systems accomplish fast response within a small fraction of a fundamental cycle by tracking the line voltages closely, and switch on the compensator whenever the voltage waveform deviates from the normal values. However, the utility voltages often contain transient spikes with amplitudes up to 200% resulting from switching of power factor-correction capacitors, circuit breaker switchings, lightning strikes, and so on. Such transient disturbances may trigger the sag compensator into operation; its controller is very sensitive. The switching frequency of the sag compensator inverter is inadequate to compensate the narrow pulses of voltage spikes. Furthermore, the power semiconductor devices (like insulated gate bipolar transistors) of the inverter may also be damaged due to overvoltage by the spikes. In this paper, a brief overview of power quality issues of a high-tech industry in Taiwan is provided to validate the need for ride-through technologies. A synchronous-reference-frame-based controller for the inverter-based voltage compensator is also presented. A sag detection mechanism is included in the controller for correct and prompt identification of voltage sags. Disturbances like voltage spikes are attenuated to avoid any false triggering of the compensator. The overall system responds to voltage sags and restores the voltage back to balance.

1.0 pu for critical loads within one-eighth to one-fourth of a cycle, which meets the requirement of industry standards like the SEMI-F47 standard. Simulation and laboratory test results are presented to verify the functionality of the proposed system.

Index Terms:

[circuit breakers](#) [compensation](#) [invertors](#) [power capacitors](#) [power factor correction](#) [power supply quality](#) [power system faults](#) [SEMI-F47 standard](#) [Taiwan](#) [circuit breakers switching](#) [false triggering avoidance](#) [high-tech manufacturers](#) [industrial customers](#) [insulated gate bipolar transistors](#) [inverter-based voltage sag compensator](#) [lightning strikes](#) [line voltage tracking](#) [manufacturing processes interruption](#) [power quality problems](#) [power semiconductor devices](#) [power-factor-correction capacitors](#) [ride-through technologies](#) [sag compensator](#) [sag compensator inverter](#) [sag detection mechanism](#) [sensitive loads](#) [series voltage sag compensator](#) [short-duration power outages](#) [switching frequency](#) [synchronous-reference frame-based controller](#) [transient disturbances](#) [transient spikes](#) [undervoltage faults](#) [uninterruptible power supplies](#) [utility conditions](#) [voltage spikes](#) [voltage waveforms](#)

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